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** CONTINUING DATA ***** *none*

** FOREIGN APPLICATIONS *****

JAPAN 2000-193104 06/27/2000
JAPAN 2000-229101 07/28/2000
JAPAN 2000-335934 11/02/2000
JAPAN 2001-11218 01/19/2001
JAPAN 2001-31901 02/08/2001
JAPAN 2001-31906 02/08/2001
JAPAN 2001-33599 02/09/2001
JAPAN 2001-35069 02/13/2001
JAPAN 2001-158662 05/28/2001
JAPAN 2001-162041 05/30/2001
JAPAN 2001-189304 06/22/2001

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Foreign Priority claimed <input checked="" type="checkbox"/> yes <input type="checkbox"/> no	STATE OR COUNTRY JAPAN	SHEETS DRAWING 50	TOTAL CLAIMS 60	INDEPENDENT CLAIMS 13
35 USC 119 (a-d) conditions met <input checked="" type="checkbox"/> yes <input type="checkbox"/> no <input type="checkbox"/> Met after Allowance				
Verified and Acknowledged <i>Paul Bertram</i> Examiner's Signature	Initials			

ADDRESS

23850

TITLE

Inspection system by charged particle beam and method of manufacturing devices using the system

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